

International Report

A word from the editor . . .

As I told you last issue, I sent my comments and most of the text for the "International Report" to our Manager of Publication on a floppy diskette. Apparently, the information was immediately usable. What I did was to prepare the material using my word processing program and then write an ASCII file to a 360K floppy disk. For those of you who send me meeting reports, news items, etc., for publication, I'd be glad to receive your material in this manner. I'll still edit the material to some extent, but much of the material will go to the publisher just the way you prepared it.

Helein D. Hitchcock, Editor

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Regional Correspondents

Australia

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Čzechoslovakia

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ICDD Announces Election of Member-at-Large and Appointments

During the Annual Meeting of the International Centre for Diffraction Data on March 22, 1990, the members in attendance elected James A. Kaduk, Amoco Corporation in Naperville, Illinois, as a Member-at-Large, resolving the tie between Kaduk and Ting C. Huang, IBM Research Division in San Jose, California, which occurred when the ballots were counted in February. The Board of Directors re-elected Gerald G. Johnson, Jr., of the Pennsylvania State University as Treasurer and elected Gregory P. Hamill, GTE Laboratories, Waltham, Massachusetts, as Chairman of the Technical Committee.

Calendar of Meetings

1990

Powder Diffraction Satellite Meeting of 15th IUCr July 16-19, 1990

Toulouse, France

The provisional list of topics includes:

1. Accuracy in data collection; high resolution diffraction; standard reference materials.
2. Sample characteristics from powder data, particularly by means of pattern fitting methods.
3. Practical aspects of structure determination from powder data: indexing, structure solution, refinement.
4. Recent applications with emphasis on time- and temperature-resolved studies of materials.
5. Advances in phase identification and quantitative analysis.

For further information: CEMES-LOE CNRS, Powder Diffraction, 29, rue Jeanne Marvig, BP 4347, 31055 Toulouse Cedex, France.

International Union of Crystallography 15th General Assembly and International Congress July 19-28, 1990

Bordeaux, France

Contact: Prof. M. Hospital, Laboratoire de Cristallographie et de Physique Cristalline, Université de Bordeaux 1, 351 Cours de la Liberation, F 33405 Talence Cedex, France.

1990 Annual Denver Conference on Applications of X-Ray Analysis July 30-August 3, 1990

Steamboat Springs, Colorado, USA.

The general area of emphasis this year is X-Ray Fluorescence. The Plenary Session topic is Surface and Near Surface X-Ray Spectroscopy. Special Session Topics include: Problems in the Determination of Low Concentration Levels by X-Ray Spectrometry, Long Wave-Length X-Ray Spectrometry, Geological Applications of X-Ray Spectrometry, XRF in Analytical Problem Solving, Non-Ambient Applications of XRD, X-Ray Scattering from Polymers, Solid State and Position-Sensitive Detectors for XRD, and Applications of PC's in Powder Diffraction. Scheduled Tutorial Workshops are: Introduction to Fundamental Parameters Procedures in XRF, Sample Preparation Methods for XRF, Open Session on Problems in XRF, Total Reflection XRF Analysis, Quantitative Phase Analysis for Environmentally Sensitive Materials, Influence of Systematic Experimental Errors on Phase Identification Using the Powder Diffraction File, Profile Fitting in XRD, Indexing Methods for Powder Diffraction Patterns, and Precision Measurement of Lattice Parameters.

Contact: Lynne Bonno, Conference Secretary, Department of Engineering, University of Denver, Denver, CO 80208, USA. Phone (303) 871-3515.

14th Conference on Applied Crystallography August 5-8, 1990

Cieszyn, Poland

The conference is organized by the Institute of Physics and Chemistry of Metals at the Silesian University in Katowice

jointly with the Institute of Ferrous Metallurgy in Gliwice and with the support of the Crystallography Committee of Polish Academy of Sciences. The scientific program includes the following topics: (1) real structure of materials (metals, ceramics, polymers, etc.); (2) research methods and equipments (phase identification, precision measurements of lattice constants, determination of crystallite sizes and distortions, texture, high temperature X-ray techniques, small-angle scattering, X-ray topography, etc.).

Contact: 14th Conference on Applied Crystallography, Uniwersytet Slaski, Instytut Fizyki i Chemii Metali, Dr. Eugeniusz Lagiewka, ul. Bankowa 12, 40-007 Katowice, Poland. Phone 59-69-29.

Rietveld Summer School for Beginners

August 9-11, 1990

Cieszyn, Poland

The school is organized by the Commission on Powder Diffraction, IUCr, Silesian University (Katowice, Poland), Institute of Ferrous Metallurgy (Gliwice, Poland) with the financial support of the International Union of Crystallography and will be held just after closing the 14th Conference on Applied Crystallography. The school will give the opportunity to acquire the basic features and present applications of the Rietveld method, and will consist of lectures and practical training.

Contact: Summer School RSSB-90, Uniwersytet Slaski, Instytut Fizyki i Chemii Metali, Dr. Eugeniusz Lagiewka, ul. Bankowa 12, 40-007 Katowice, Poland. Phone 59-69-29.

International Conference on Advanced Methods in X-Ray and Neutron Structure Analysis of Materials

August 20-24, 1990

Prague, Czechoslovakia

The conference will cover the following three areas: (1) powder diffraction and real structure; (2) diffraction analysis of physical phenomena; (3) crystal and molecular structures.

Contact: Dr. V. Petricek, Institute of Physics CSAV, Na Slovance 2, 18040 Prague 8, Czechoslovakia

JCPDS-International Centre for Diffraction Data

Fall Technical Meetings

October 16-18, 1990

Concordville, Pennsylvania, USA.

Contact: Ms. Josephine Felizzi, JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, PA 19081, USA. Phone (215) 328-9403.

Materials Research Society Fall Meeting

November 26-December 1, 1990

Boston, Massachusetts, USA

Contact: M. Geil, Materials Research Society, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373.

1991

JCPDS-International Centre for Diffraction Data

Spring Technical Meetings and Annual Meeting

March 19-21, 1991

Concordville, Pennsylvania, USA.

Contact: Ms. Josephine Felizzi, JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, PA 19081, USA. Phone (215) 328-9403.

Materials Research Society Spring Meeting

April 29-May 4, 1991

Anaheim, California, USA

Contact: M. Geil, Materials Research Society, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373.

PICXAM

Pacific-International Congress on X-Ray Analytical Methods

August 12-16, 1991

Honolulu, Hawaii, USA

The major thrust of this meeting will be the practical aspects involved in X-ray methods for materials analysis. The Congress will provide an international forum for discussion of the following methods: X-ray powder diffraction, X-ray fluorescence, X-ray aspects of surface analysis, X-ray emission, X-ray stress analysis, and thin film analysis by X-ray powder diffraction and X-ray fluorescence. Workshops will be offered at the University of Hawaii at Hilo on the island of Hawaii on August 7-9, the Wednesday through Friday preceding the Congress. Proceedings will be published as a volume of *Advances in X-Ray Analysis* with Paul Predecki as the Coordinating Editor.

Contact: Lynne Bonno, Conference Secretary, Department of Engineering, University of Denver, Denver, CO 80208, USA. Phone (303) 871-3515.

JCPDS-International Centre for Diffraction Data

Fall Technical Meetings

October 1991

Philadelphia area (to be announced), Pennsylvania, USA.

Contact: Ms. Josephine Felizzi, JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, PA 19081, USA. Phone (215) 328-9403.

Materials Research Society Fall Meeting

December 2-7, 1991

Boston, Massachusetts, USA

Contact: M. Geil, Materials Research Society, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373.